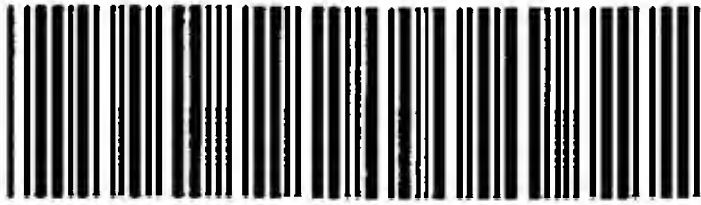


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/709,267	WU, KE	
	Examiner	Art Unit	
	Linh V. Nguyen	2819	

SEARCHED			
Class	Subclass	Date	Examiner
330	251,152 257,259 260,261	3/28/2005	LN
327	52,87 206	3/28/2005	LN
326	65,71 81	3/28/2005	LN
326	83	3/28/2005	LN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
327	206	3/28/2005	LN
326	83	3/28/2005	LN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
gate, self bias, current source, current sink, pull up, pull down, differential , bias	3/28/2005	LN